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Examiner Thomas L. Dickey, GAU 2826
U.S. Patent and Trademark Office

From: Mitchell S. Bigel

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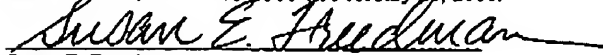
Re: **Deok-Hyung Lee et al., *Integrated Circuit Field Effect Transistors Including Channel-Containing Fin Having Regions of High and Low Doping Concentration*, Serial No. 10/801,614, filed March 16, 2004**

Attached are the following documents responsive to the Advisory Action dated February 10, 2006:

1. Request for Continued Examination (RCE) Transmittal; and
2. Applicant Initiated Interview Request Form.

CERTIFICATION OF FACSIMILE TRANSMISSION
UNDER 37 CFR § 1.8

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Attorney Docket No. 5649-1272

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Deok-Hyung Lee et al.

Confirmation No.: 2903

Serial No.: 10/801,614

Examiner: Thomas L. Dickey

Filed: March 16, 2004

Group Art Unit: 2826

For: INTEGRATED CIRCUIT FIELD EFFECT TRANSISTORS INCLUDING CHANNEL-
CONTAINING FIN HAVING REGIONS OF HIGH AND LOW DOPING
CONCENTRATIONS

February 28, 2006

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

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APPLICANT INITIATED INTERVIEW REQUEST FORM

Sir:

Tentative Participants:

1. Examiner Thomas L. Dickey2. Mitchell S. Bigel

3. _____

4. _____

Proposed Date of Interview: _____ Proposed Time: _____

At the Examiner's convenience.

Type of Interview Requested:

(1) ☒ Telephonic(2) ☐ Personal(3) ☐ Video ConferenceExhibit to be shown or demonstrated ☐ YES☒ NO

If yes, provide brief description:

ISSUES TO BE DISCUSSED

Issues (Rej., Obj., etc.) Fig. #s	Claims/ Prior Art	Discussed	Agreed	Not Agreed
1) <u>Rejection</u>	<u>Claims 1, 13</u>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
2) _____	_____	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
3) _____	_____	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
4) _____	_____	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>

☐ Continuation Sheet Attached

Brief Description of Arguments to be Presented:

Discuss the scope and meaning of "confined laterally to beneath the channel region" and possible modification of this language per the Examiner's suggestion.

An interview was conducted on the above-identified application on _____.

Applicant/Applicant's Representative Signature_____
Examiner/SPE Signature